

## SVT\_GP MODELS (NSVTGP, PSVTGP)

### 1. CONDITIONS OF EXTRACTION

- Maturity: Preliminary
- Model parameters extraction based on lot : -
- Geometrical extraction domain:
  - Drawn gate length :  $0.18 \geq L \geq 0.06 \mu\text{m}$
  - Drawn transistor width :  $10 \geq W \geq 0.12 \mu\text{m}$
- Temperature extraction domain:  $-40^\circ\text{C}$  to  $150^\circ\text{C}$
- Bias extraction domain:
  - Gate bias:  $0 \leq |V_{GS}| \leq 1.1 \text{ V (VDD + 10\%)}$
  - Drain bias:  $0 \leq |V_{DS}| \leq 1.1 \text{ V (VDD + 10\%)}$
  - Bulk bias:  $0 \leq |V_{BS}| \leq 1.1 \text{ V (VDD + 10\%)}$

### 2. CONDITIONS OF SIMULATION

- Temperature:  $25^\circ\text{C}$
- Currents:
  - $I_{DLIN} = I_{ds}$  at  $V_{gs} = 1.0 \text{ V}$ ,  $V_{ds} = 50 \text{ mV}$  and  $V_{bs} = 0 \text{ V}$
  - $I_{ON} = I_{ds}$  at  $V_{gs} = 1.0 \text{ V}$ ,  $V_{ds} = 1.0 \text{ V}$  and  $V_{bs} = 0 \text{ V}$
  - $I_{OFF} = I_{ds}$  at  $V_{gs} = 0 \text{ V}$ ,  $V_{ds} = 1.0 \text{ V}$  and  $V_{bs} = 0 \text{ V}$
  - $I_{G\_ON} = I_{gs}$  at  $V_{gs} = 1.0 \text{ V}$  and  $V_d = V_s = V_b = 0 \text{ V}$
  - $I_{G\_OFF} = I_{gs}$  at  $V_{gs} = V_{bs} = 0 \text{ V}$  and  $V_{ds} = 1.0 \text{ V}$
- Threshold voltage in linear and saturation regime
  - $V_{TLIN}$  is  $V_{gs}$  value at  $V_{ds} = 50 \text{ mV}$ ,  $V_{bs} = 0 \text{ V}$  and  $I_{ds} = 40 \cdot W/L \text{ nA}$ .
  - $V_{TSAT}$  is  $V_{gs}$  value at  $V_{ds} = 1.0 \text{ V}$ ,  $V_{bs} = 0 \text{ V}$  and  $I_{ds} = 40 \cdot W/L \text{ nA}$ .
- Current derivatives:

$$G_m = \frac{\partial}{\partial V_{gs}} I_{ds} \text{ at } V_{gs} = V_{TLIN} + 0.2 \text{ V}, V_{ds} = 0.5 \text{ V and } V_{bs} = 0 \text{ V}$$

$$G_d = \frac{\partial}{\partial V_{ds}} I_{ds} \text{ at } V_{gs} = V_{TLIN} + 0.2 \text{ V}, V_{ds} = 0.5 \text{ V and } V_{bs} = 0 \text{ V}$$

$$\text{Analog gain} = G_m/G_d$$

- Gate Capacitances:

CGGINV = CGG at  $V_{gs} = 1.0 \text{ V}$ ,  $V_{ds} = 0 \text{ V}$  and  $V_{bs} = 0 \text{ V}$

CGD\_0V = CGD at  $V_{gs} = 0 \text{ V}$ ,  $V_{ds} = 0 \text{ V}$  and  $V_{bs} = 0 \text{ V}$

$$CGGMEAN = \frac{1}{VDD} \cdot \int_0^{VDD} CGG \times dV_{gs} \text{ with } VDD = 1.0 \text{ V and } V_{bs} = 0 \text{ V}$$

TAU = CGGMEAN\*VDD/ION

- Diode Capacitances:

CBD OFF = CBD at  $V_{gs} = 0 \text{ V}$ ,  $V_{ds} = 1.0 \text{ V}$  and  $V_{bs} = 0 \text{ V}$

**Note:** the area and perimeters of source/drain junction diodes used for simulation are defined with the the minimum poly-to-active distance specified in the DRM.

- Transition frequency:

FT = frequency for which the small signal current gain  $H_{21}$  is 0 dB (i.e.  $\left| \frac{I_d}{I_g} \right| = 0 \text{ dB}$ ).

### 3. MAIN ELECTRICAL CHARACTERISTICS OF NMOS SVT\_GP TRANSISTORS

PARAMETERS	SVTGP_TT	SVTGP_SS	SVTGP_FF	units
N-channel transistors (nsvtgp)				
VTLIN W=1/L=0.18	274	300	249	mV
IDLIN W=1/L=0.18	4.56e-05	4.12e-05	5.04e-05	A
VTSAT W=1/L=0.18	244	269	218	mV
ION W=1/L=0.18	2.53e-04	2.20e-04	2.89e-04	A
VTLIN W=1/L=0.06	245	296	187	mV
IDLIN W=1/L=0.06	1.27e-04	1.11e-04	1.46e-04	A
VTSAT W=1/L=0.06	115	178	44	mV
ION W=1/L=0.06	8.10e-04	6.76e-04	9.70e-04	A
IOFF W=1/L=0.06	5.09e-08	1.12e-08	2.58e-07	A
IG_ON W=1/L=0.06	6.77e-09	3.38e-09	1.37e-08	A
IG_OFF W=1/L=0.06	1.10e-09	5.57e-10	2.20e-09	A
FT W=1/L=0.06	2.97e+11	2.65e+11	3.35e+11	Hz
CGGinv W=1/L=0.06	8.04e-16	8.51e-16	7.52e-16	F
CGGmean W=1/L=0.06	7.72e-16	7.97e-16	7.39e-16	F
CGD 0V W=1/L=0.06	3.44e-16	3.40e-16	3.48e-16	F
CBD OFF <sup>a</sup> W=1/L=0.06	4.85e-16	5.50e-16	4.17e-16	F
Tau W=1/L=0.06	1.0	1.2	0.8	ps
Gm W=1/L=0.06	5.20e-04	4.75e-04	5.69e-04	S
Gd W=1/L=0.06	8.02e-05	6.74e-05	9.56e-05	S
Gain W=1/L=0.06	6.49e+00	7.05e+00	5.94e+00	
VTLIN W=0.12/L=0.06	208	259	152	mV
IDLIN W=0.12/L=0.06	1.75e-05	1.50e-05	2.03e-05	A
VTSAT W=0.12/L=0.06	107	165	41	mV
ION W=0.12/L=0.06	1.08e-04	8.74e-05	1.32e-04	A
IOFF W=0.12/L=0.06	7.43e-09	1.80e-09	3.33e-08	A
FT W=0.12/L=0.06	2.28e+11	1.97e+11	2.67e+11	Hz

Table 1: Main electrical characteristics for NMOS

a. Value corresponding to the minimum poly-to-active distance specified in the DRM

#### 4. MAIN ELECTRICAL CHARACTERISTICS OF PMOS SVT\_GP TRANSISTORS

PARAMETERS	SVTGP_TT	SVTGP_SS	SVTGP_FF	units
P-channel transistors (psvtgp)				
VTLIN W=1/L=0.18	191	218	165	mV
IDLIN W=1/L=0.18	2.09e-05	1.88e-05	2.33e-05	A
VTSAT W=1/L=0.18	155	182	127	mV
ION W=1/L=0.18	1.70e-04	1.47e-04	1.96e-04	A
VTLIN W=1/L=0.06	249	300	186	mV
IDLIN W=1/L=0.06	4.55e-05	3.89e-05	5.35e-05	A
VTSAT W=1/L=0.06	140	202	60	mV
ION W=1/L=0.06	3.82e-04	3.07e-04	4.84e-04	A
IOFF W=1/L=0.06	2.46e-08	4.84e-09	1.75e-07	A
IG_ON W=1/L=0.06	5.06e-09	2.31e-09	1.19e-08	A
IG_OFF W=1/L=0.06	1.02e-09	5.09e-10	2.06e-09	A
FT W=1/L=0.06	1.32e+11	1.11e+11	1.58e+11	Hz
CGGinv W=1/L=0.06	8.66e-16	9.32e-16	8.03e-16	F
CGGmean W=1/L=0.06	8.11e-16	8.47e-16	7.74e-16	F
CGD 0V W=1/L=0.06	3.33e-16	3.20e-16	3.43e-16	F
CBD OFF <sup>a</sup> W=1/L=0.06	5.00e-16	5.66e-16	4.30e-16	F
Tau W=1/L=0.06	2.1	2.8	1.6	ps
Gm W=1/L=0.06	2.89e-04	2.54e-04	3.35e-04	S
Gd W=1/L=0.06	4.13e-05	3.12e-05	5.81e-05	S
Gain W=1/L=0.06	6.99e+00	8.15e+00	5.76e+00	
VTLIN W=0.12/L=0.06	166	223	91	mV
IDLIN W=0.12/L=0.06	6.90e-06	5.92e-06	8.02e-06	A
VTSAT W=0.12/L=0.06	69	136	-16	mV
ION W=0.12/L=0.06	6.05e-05	4.83e-05	7.66e-05	A
IOFF W=0.12/L=0.06	1.31e-08	2.24e-09	1.18e-07	A
FT W=0.12/L=0.06	9.22e+10	7.80e+10	1.06e+11	Hz

Table 2: Main electrical characteristics for PMOS

a. Value corresponding to the minimum poly-to-active distance specified in the DRM

## 5. ION, IOFF, VT BEHAVIOR VERSUS GATE LENGTH AND CHANNEL WIDTH FOR NMOS SVT\_GP TRANSISTORS

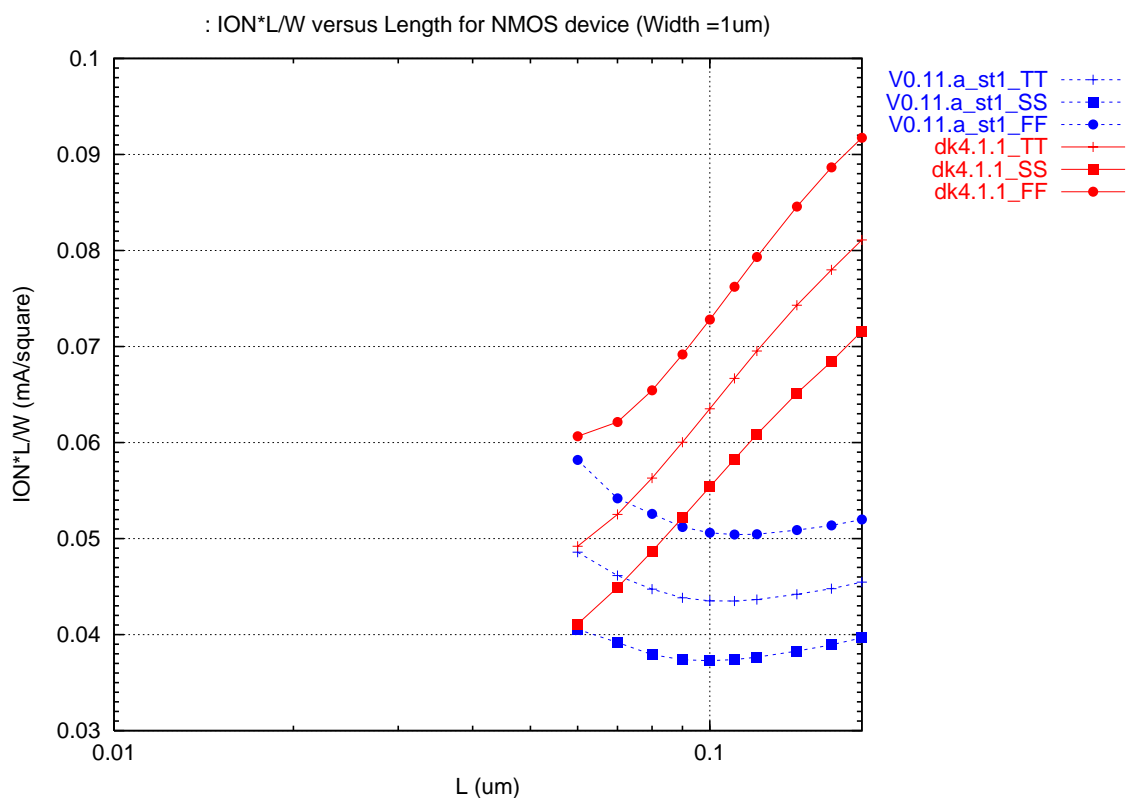


Figure 1 :  $I_{ON}/\square = I_{ON} \cdot L/W$  versus drawn gate length for NMOS SVT\_GP transistors ( $W = 1 \mu m$ )

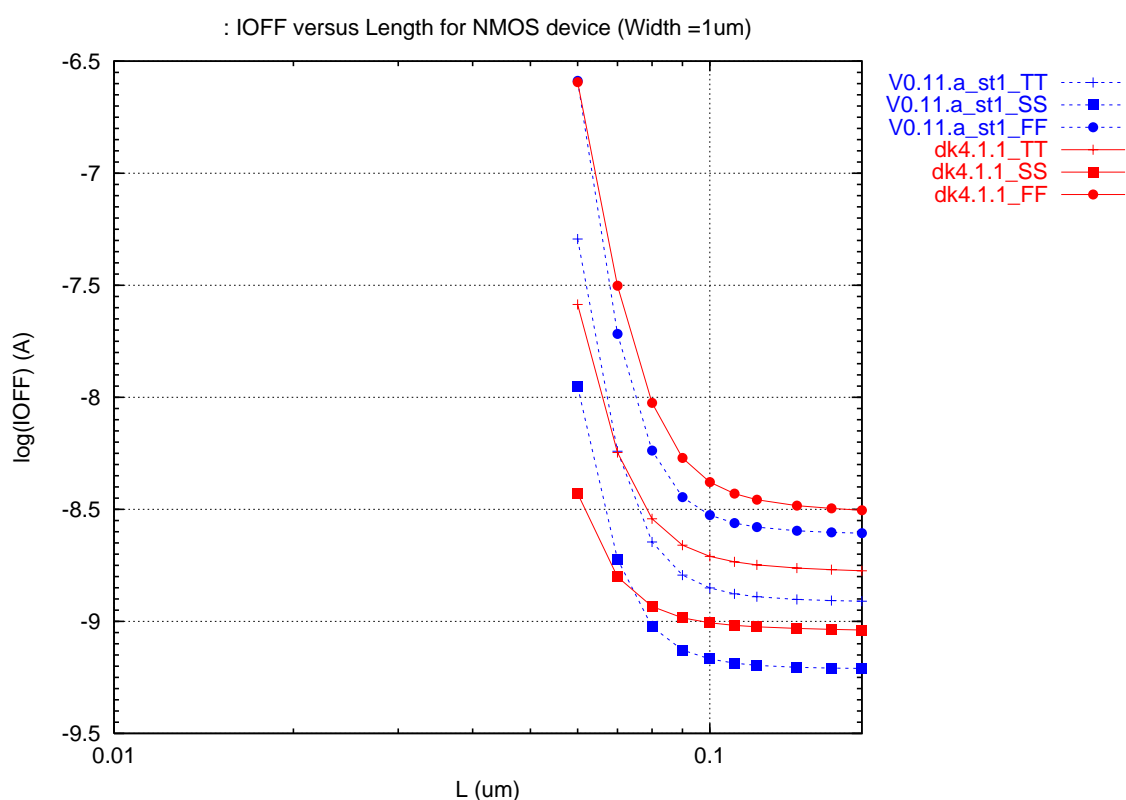


Figure 2 : IOFF versus drawn gate length for NMOS SVT\_GP transistors ( $W = 1 \mu m$ )

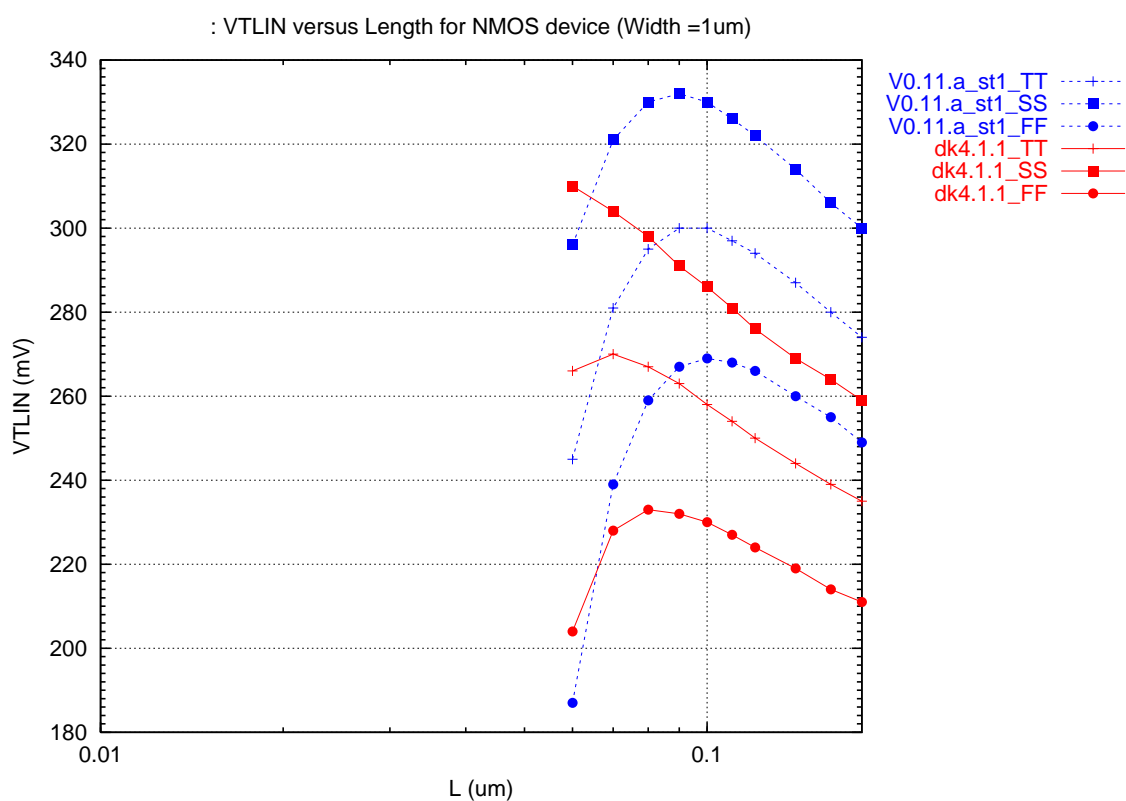


Figure 3 : Threshold voltage VTLIN versus drawn gate length for NMOS SVT\_GP transistors ( $W = 1 \mu\text{m}$ )

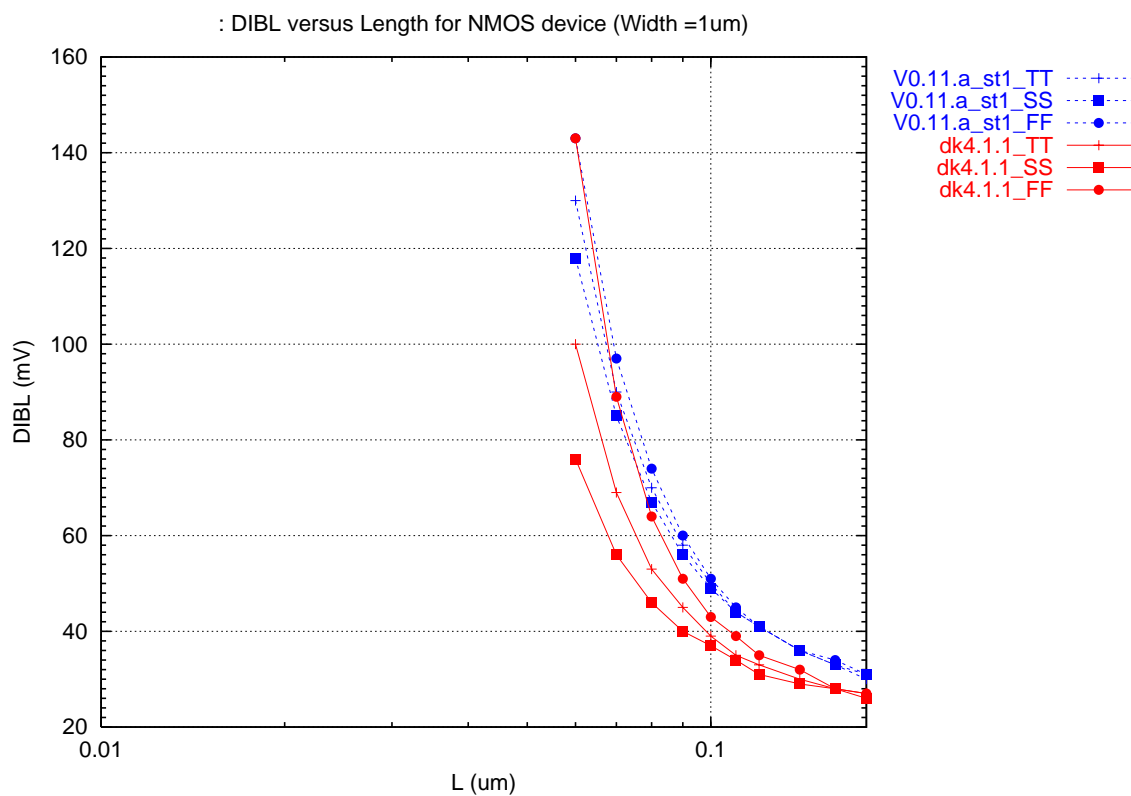


Figure 4 : DIBL= VTLIN-VTSAT versus drawn gate length for NMOS SVT\_GP transistors ( $W = 1 \mu\text{m}$ )

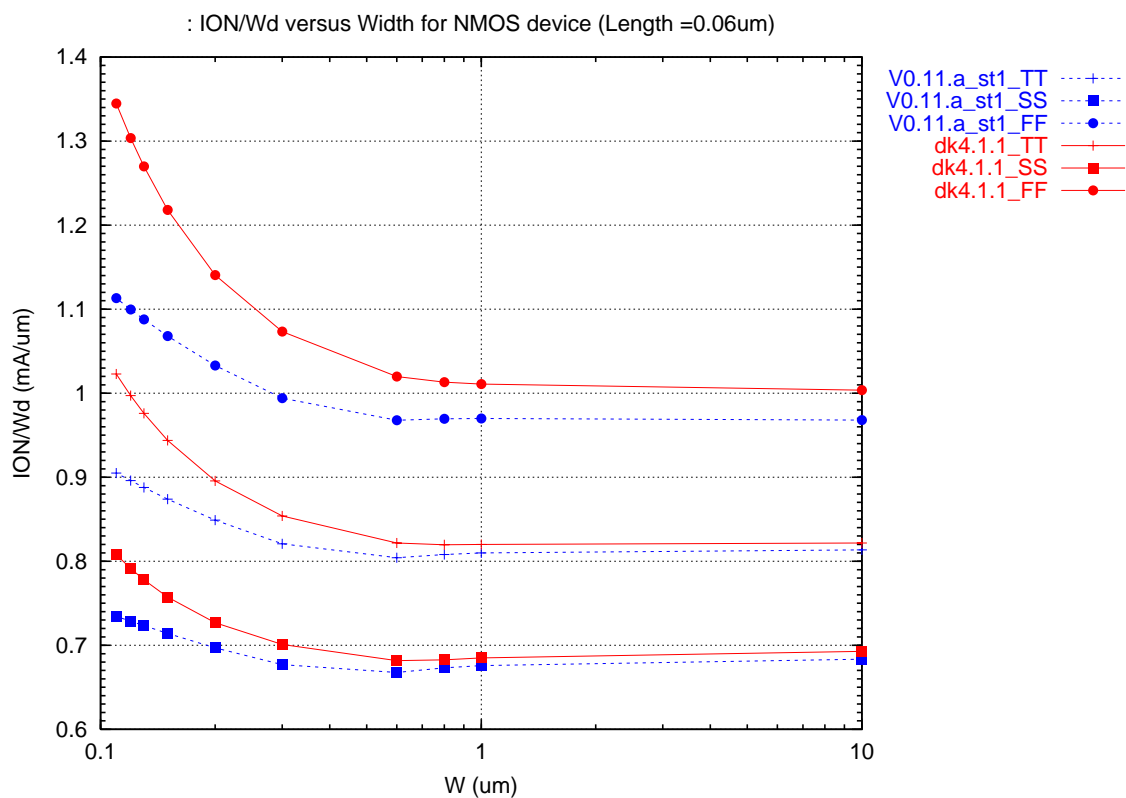


Figure 5 : ION versus drawn channel width for NMOS SVT\_GP transistors (L = 0.06 μm)

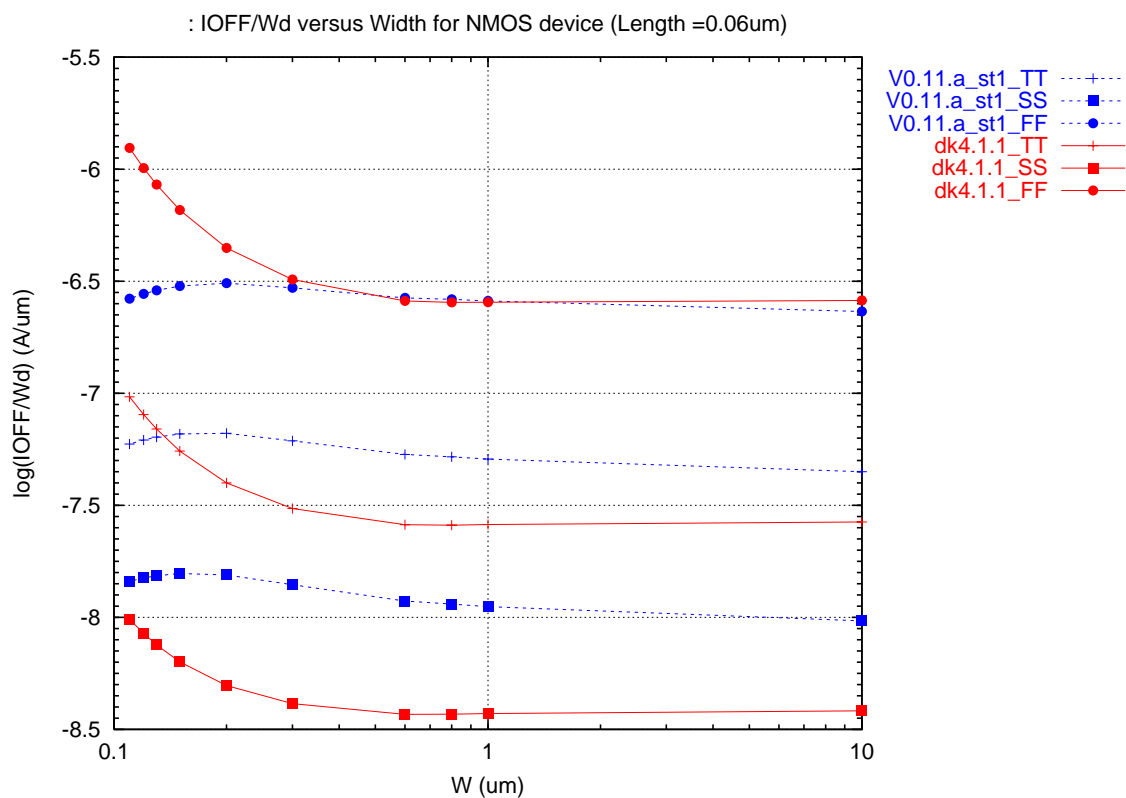


Figure 6 : IOFF versus drawn channel width for NMOS SVT\_GP transistors (L = 0.06 μm)

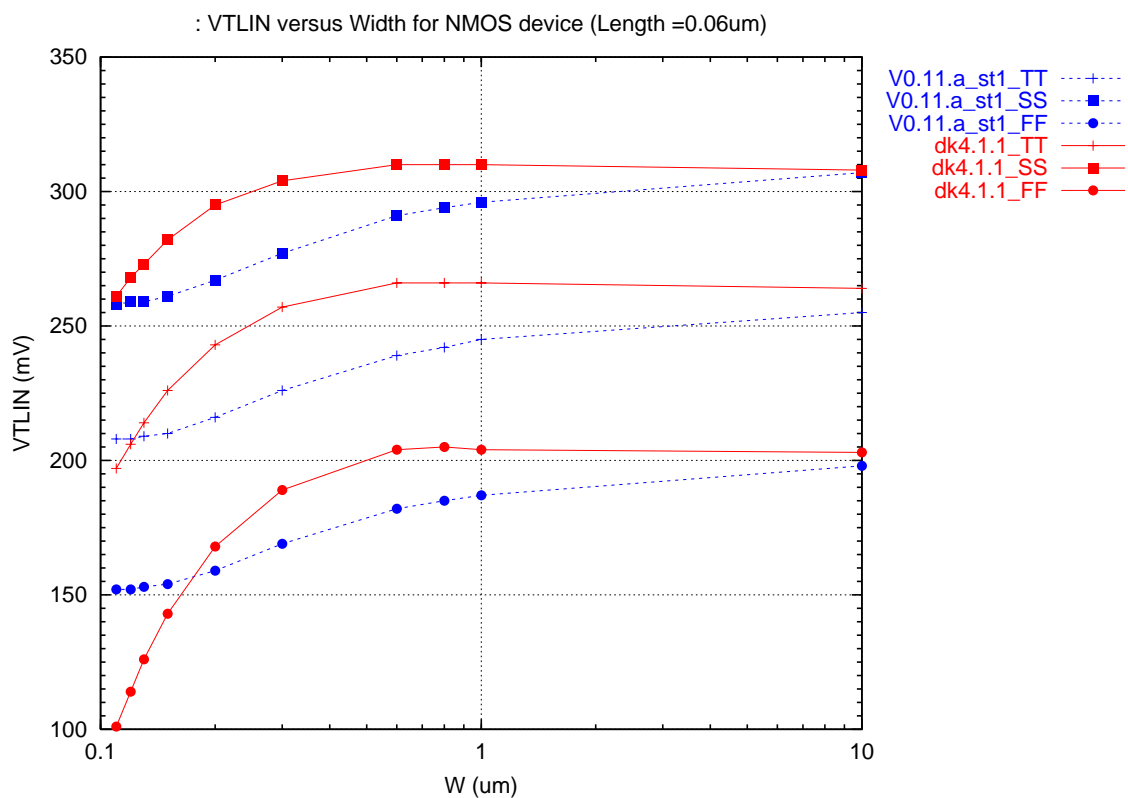


Figure 7 : Threshold voltage VTLIN versus drawn channel width for NMOS SVT\_GP transistors ( $L = 0.06 \mu\text{m}$ )



## 6. ION, IOFF, VT BEHAVIOR VERSUS GATE LENGTH AND CHANNEL WIDTH FOR PMOS SVT\_GP TRANSISTORS

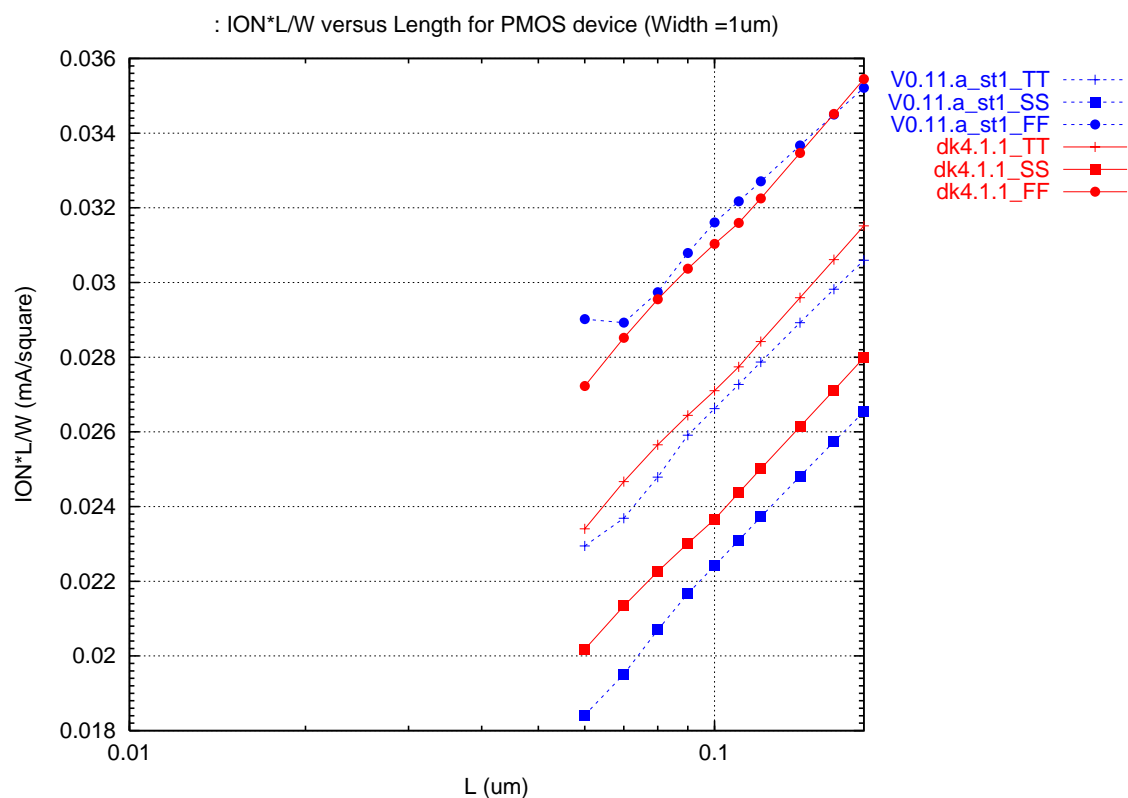


Figure 8 : ION versus drawn gate length for PMOS SVT\_GP transistors (W = 1  $\mu$ m)

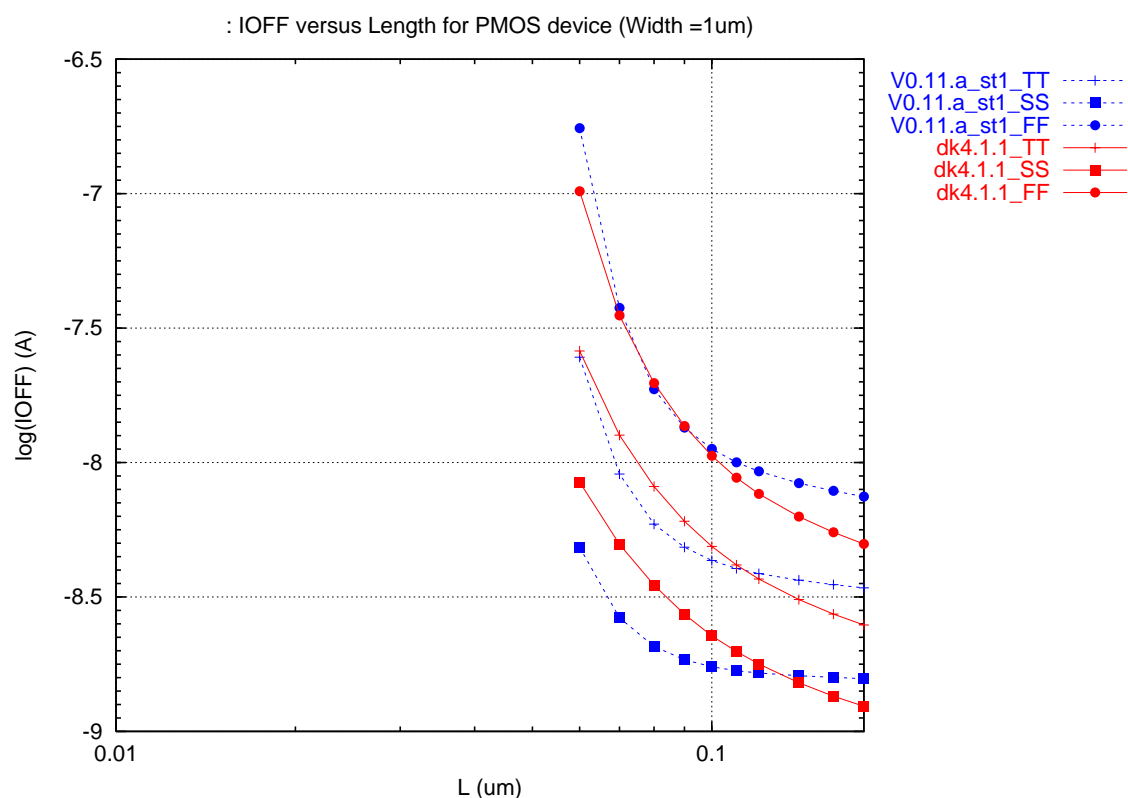


Figure 9 : IOFF versus drawn gate length for PMOS SVT\_GP transistors (W = 1  $\mu$ m)

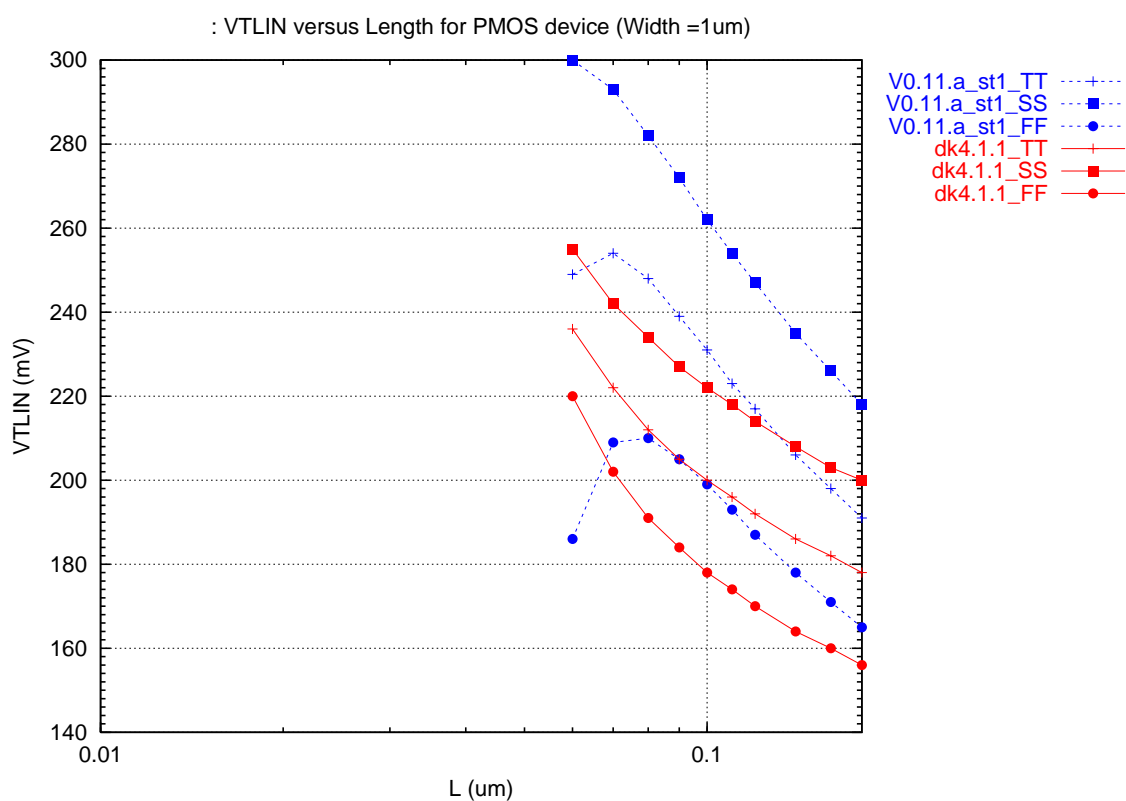


Figure 10 : Threshold voltage VTLIN versus drawn gate length for PMOS SVT\_GP transistors ( $W = 1 \mu\text{m}$ )

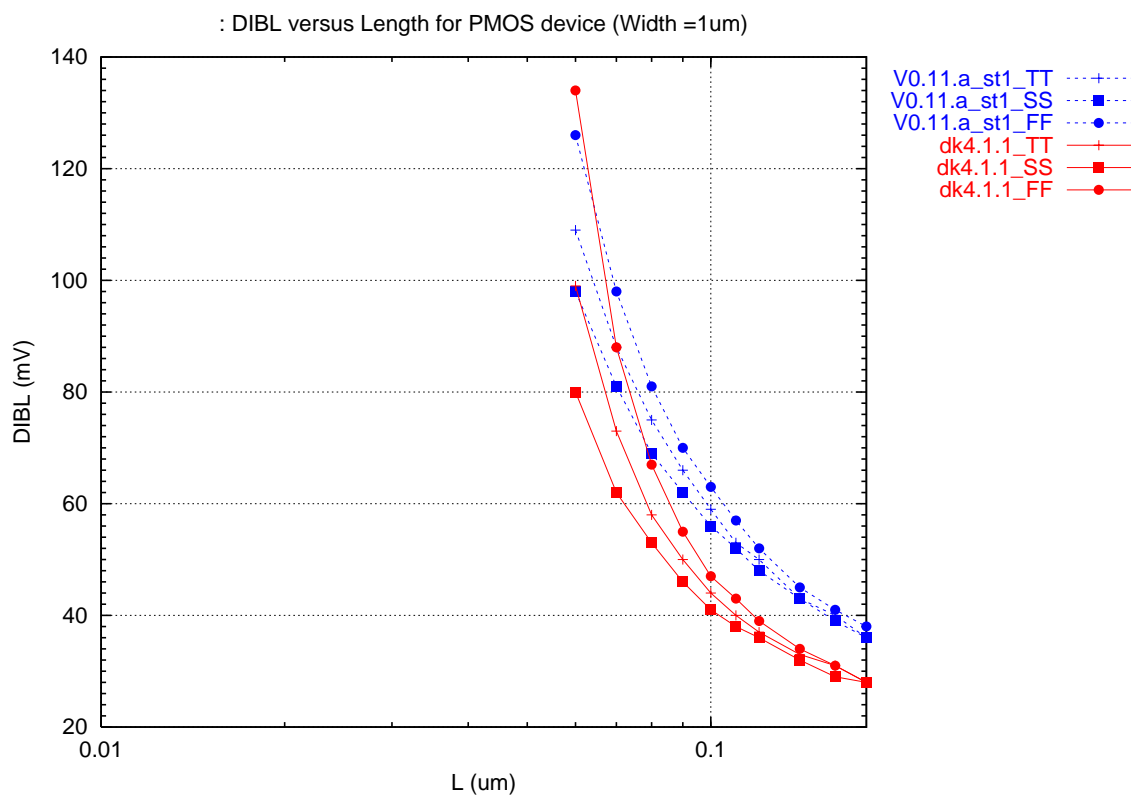


Figure 11 : DIBL= VTLIN-VTSAT versus drawn gate length for PMOS SVT\_GP transistors ( $W = 1 \mu\text{m}$ )

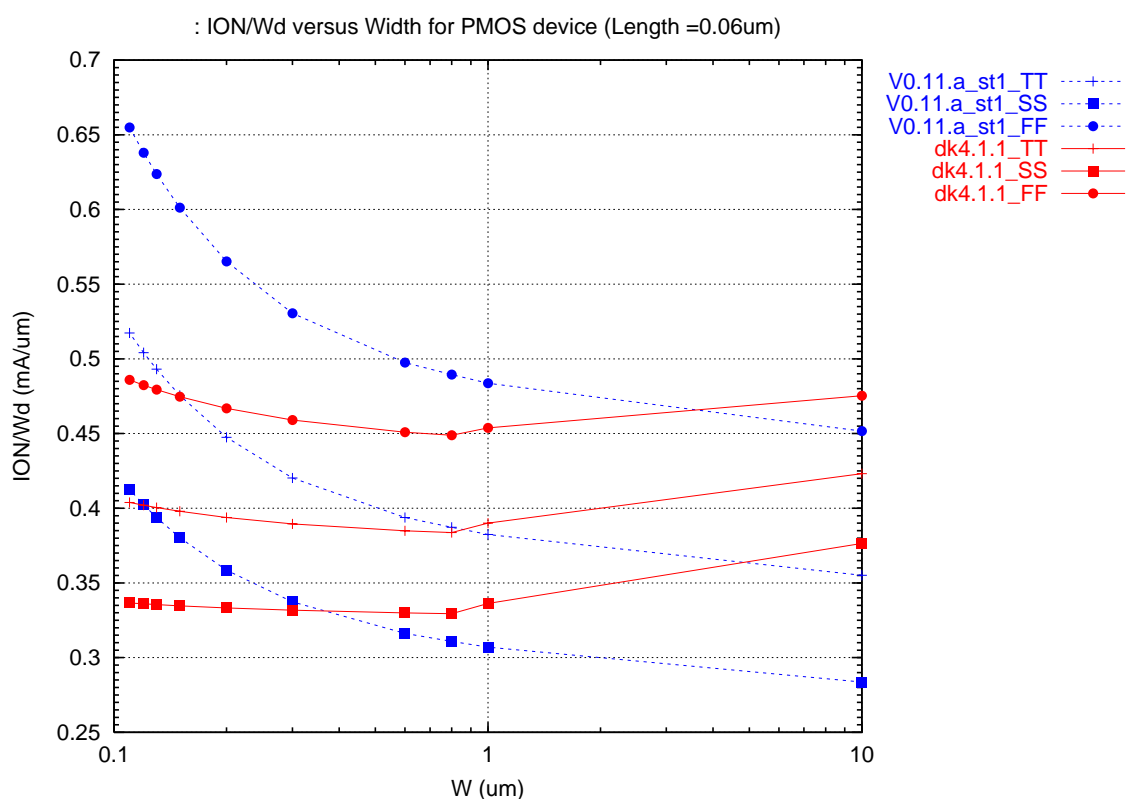


Figure 12 : ION versus drawn channel width for PMOS SVT\_GP transistors ( $L = 0.06 \mu\text{m}$ )

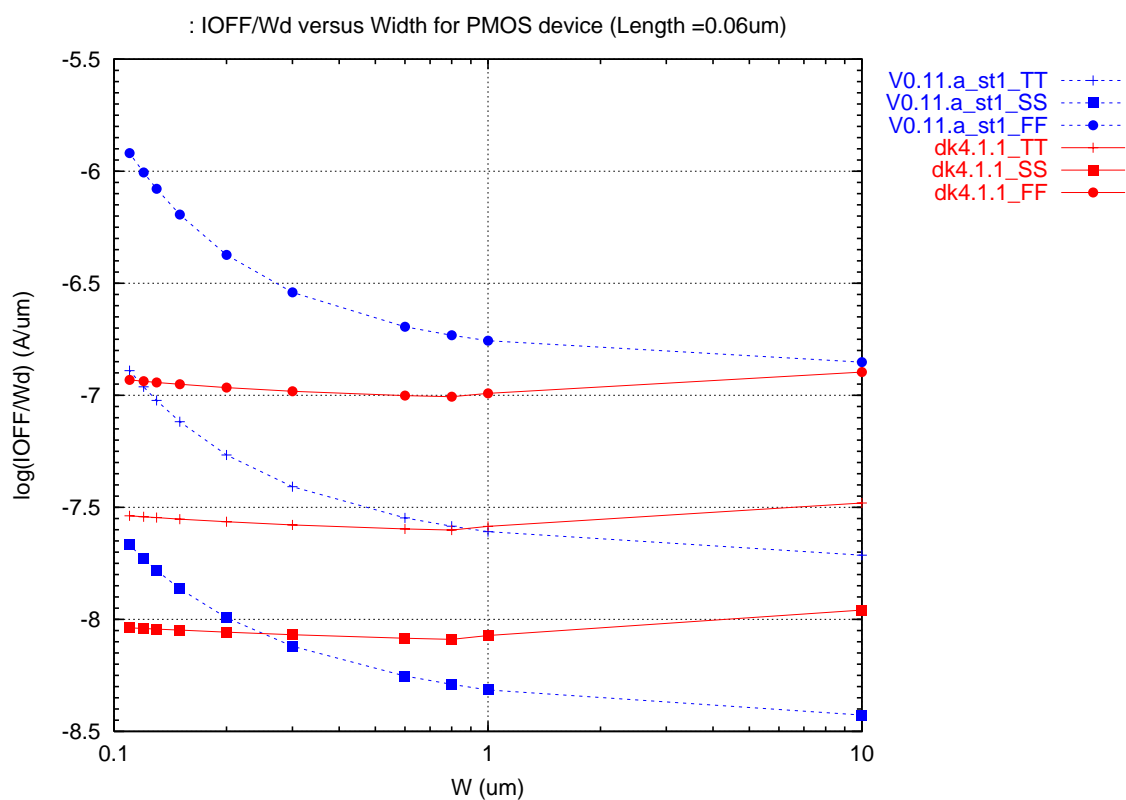


Figure 13 : IOFF versus drawn channel width for PMOS SVT\_GP transistors ( $L = 0.06 \mu\text{m}$ )

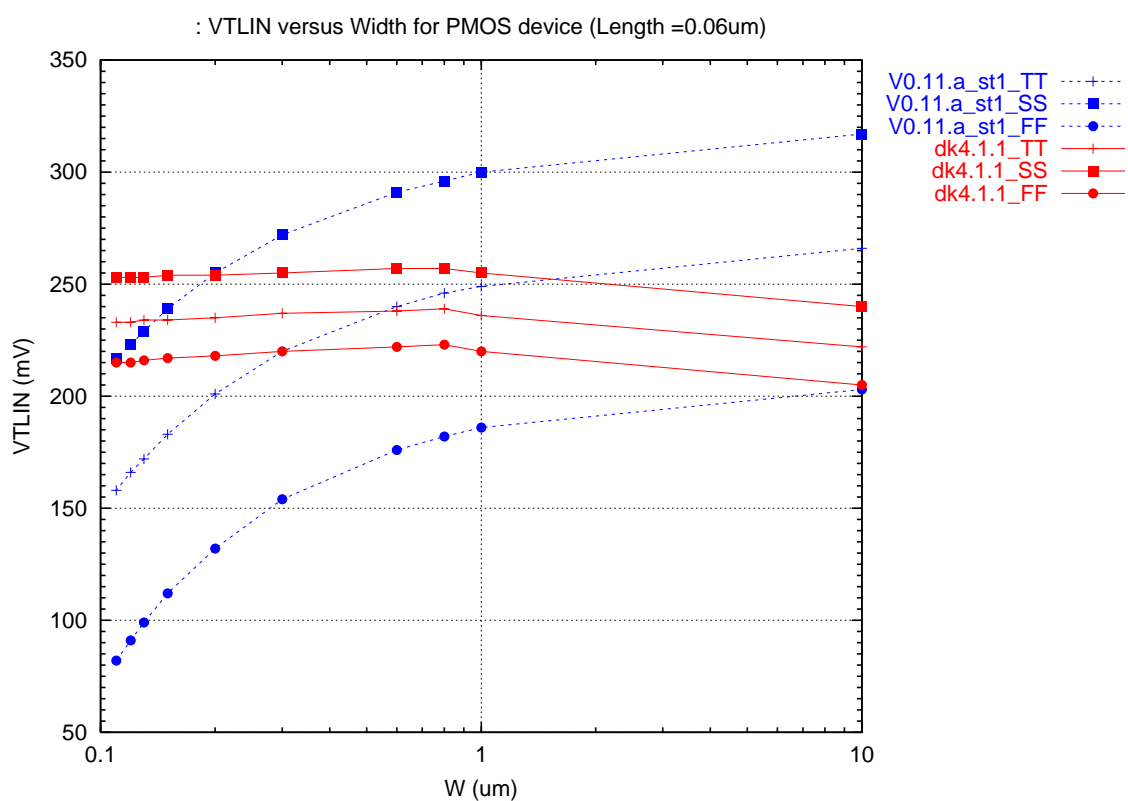


Figure 14 : Threshold voltage VTLIN versus drawn channel width for PMOS SVT\_GP transistors (L = 0.06